## **PRODUCT INFORMATION NOTICE**

1. TITLE		2. DOCUMENT NUMBER		
Add RHA notations to clarify the environmental dose rate for which the UT699 LEON is guaranteed		SPO-2014-PIN-0005		
		3. DATE (Year, Month, Date) 2014, November, 21		
4. MANUFACTURER NAME AND ADDRESS CAES 4350 CENTENNIAL BOULEVARD COLORADO SPRINGS, COLORADO 80907-3486		5. MANUFACTURER POINT OF CONTACT NAME Tim Meade		
		6. MANUFACTURER POINT OF CONTACT TELEPHONE		
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		tim.l.meade@cobhamaes.com		
8. CAGE CODE 65342	9. BLANK	10. PRODUCT IDENTIFICATION CODE WG07	11. base part UT699	
12. BLANK		13. SMD NUMBER 08228	14. DEVICE TYPE DESIGNATOR	
u da se		15. RHA LEVELS	16. QML LEVEL	
		ALL	ALL	
		ALL 17. NON QML LEVEL	ALL 18. BLANK	
19. DESCRIPTION	I (FOR NEW PRODUCTS, PROVIDE AVAILABILITY DATE AND I	17. NON QML LEVEL N/A		
The UT699 (SM SMD lists a dos rad (Si)/sec dos	I (FOR NEW PRODUCTS, PROVIDE AVAILABILITY DATE AND I I/D#5962-08228) is guaranteed to a maximum radia se rate of 50-300 rad (Si)/sec with the maximum tota se rate refers to the MIL-STD-883 test method 1019 se is guaranteed.	17. NON QML LEVEL N/A .EAD TIME) tion hardness assurance (RHA) leve al dose available specification. The S	18. BLANK I of 100K rad(Si). The current SMD is unclear if the 50-300	
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The UT699 (SM SMD lists a do rad (Si)/sec do which the device The proper inte which CAES in whose dose ra required for the	<i>ID#5962-08228</i> ) is guaranteed to a maximum radia se rate of 50-300 rad (Si)/sec with the maximum tota se rate refers to the MIL-STD-883 test method 1019 se is guaranteed. erpretation is that the 50-300 rad (Si)/sec dose rate a adiates the device during its RHA qualification testi te is $\leq$ 1 rad (Si)/sec. Due to a parametric failure of	17. NON QML LEVEL N/A EAD TIME) tion hardness assurance (RHA) leve al dose available specification. The S condition A dose rate or the user's e always refers to the MIL-STD-883, m ng. The devices offered in the SMD IDDCS (Standby core power supply	18. BLANK I of 100K rad(Si). The current SMD is unclear if the 50-300 environmental dose rate at ethod TM1019 dose rate at are intended for applications current), the anneal time	

Maximum total dose available (effective dose rate = 1 rad(Si)/s) ..... 100 krad (Si) 6/

The following note <u>6/</u> will be included in the SMD to address the irradiation dose rate and application of TM1019:

 $\underline{6}$  Device type 01 is irradiated at dose rate = 50 – 300 rad (Si)/s in accordance with MIL-STD-883, method 1019, condition A, and is guaranteed to a maximum total dose specified. The effective dose rate after extended room temperature anneal = 1 rad (Si)/s perMIL-STD-883, method 1019, condition A, section 3.11.2. The total dose specification for this device only applies to the specified effective dose rate, or lower, environment.

NOTE: THIS DOCUMENT IS PUBLISHED FOR INFORMATION PURPOSES AND MAY PROVIDE FORWARD LOOKING STATEMENTS THAT ARE SUBJECT TO CHANGE. THE USERS SHOULD CONTACT THEIR LOCAL CAES SALES OFFICE FOR ANY ACTIONABLE CONTENT DESCRIBED HEREIN.

20. ADEPT REPRESENTATIVE	21. SIGNATURE	22. DATE
Lin-Chi Huang	Sichthan	12/15/2014